

Search Notes

Application/Control No.

10/807,880

Examiner

Huyen Le

Applicant(s)/Patent under
Reexamination

MCEWAN, WAYNE E.

Art Unit

3751

SEARCHED

Class	Subclass	Date	Examiner
401	268 282 289 290	12/23/2005	HL
	136-140		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR